



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. 10/050,334
Filing Date January 15, 2002
Inventor Vishnu K. Agarwal
Assignee Micron Technology, Inc.
Group Art Unit 2813
Examiner Y. Huynh
Attorney's Docket No. MI22-1913
Title: Capacitor Constructions with Enhanced Surface Area

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References –See Attached Form PTO-1449

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. No admission is made regarding whether all the submitted references are prior art.

The listed references were cited by, or submitted to, the Office in the parent, co-pending application of the above-identified application. The above-identified application is a divisional application of co-pending application Serial No. 09/653,156, filed August 31, 2000. Such prior disclosure is sufficient for the above-identified application as far as copies of the references are concerned.

37 C.F.R. § 1.98(d) and MPEP § 609(2).

Citation of the referenced art is respectfully requested.

Respectfully submitted,

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MAR 15 2004

Dated: 04 Mar 2004

By: James E. Lake

James E. Lake
Reg. No. 44,854

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1913		SERIAL NO. 10/050,334	
<div style="border: 2px solid black; border-radius: 50%; padding: 10px; display: inline-block; text-align: center;"> OIPE MAR 04 2004 </div> LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Vishnu K. Agarwal et al			
				FILING DATE January 15, 2002		GROUP 2813	
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
AA	5,452,178	09/1995	Emesh et al				
AB	6,458,416	10/2002	Derderian et al				
AC	6,309,923	10/2001	Tseng, Horng-Huei				
AD							
AE							
AF							
AG							
AH							
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AJ							
AK							
AL							
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
AM							
AN							
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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